

<b>Notice of References Cited</b>	Application/Control No. 10/712,706	Applicant(s)/Patent Under Reexamination ROOT ET AL.	
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**U.S. PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	David E. Root, John Wood, and Nick Tufillaro; "New Techniques for Non-Linear Behavioral Modeling of Microwave/RD ICs from Simulation and Nonlinear Microwave Measurements"; June 2003; ACM; Proceedings of the 40th conference on Design Automation; pages 85-90
	V	John Wood and David E. Root; "The Behavioral Modeling of Microwave/RF ICs using Nonlinear Time Series Analysis"; June 2003; IEEE; pages 791-794
	W	David E. Root, John Wood, Nick Tufillaro, Dominique Schreurs, and Alexander Pekker; "Systematic behavioral modeling of nonlinear microwave/RF circuits in the time domain using techniques from nonlinear dynamical systems"; 2002; IEEE; pages 71-74
	X	D. Schreurs, J. Wood, N. Tufillaro, D. Usikov, L. Barford, and D.E. Root; "The Construction and Evaluation of Behavioral Models for Microwave Devices Based on Time-Domain Large-Signal Measurements"; 2000; IEEE; pages 819-822

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	U	Jens Verspecht; "Describing Functions Can Better Model Hard Nonlinearities In The Frequency Domain Than The Volterra Theory"; 1995; pages 1-17
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